

On-the-Fly Machine Learning Model for Future 3D NAND Trim Optimization

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Abstract:

On-the-Fly Trim Optimization (OFTO), a Bayesian-based method, is presented for streamlining NAND trim tuning. Applied to the latest node, OFTO improves performance and reliability by 20% and reduces development time by 80%, advancing trim design efficiency for future 3D NAND.